Docket No.

217868US2S/hc

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF:

Hideaki HAYASHI, et al.

SERIAL NO:

D: 10/028,788

GAU:

2185

FILED:

December 28, 2001

EXAMINER:

FOR:

APPARATUS MANAGEMENT METHOD, APPARATUS MANAGEMENT SYSTEM, AND APPARATUS

MANAGEMENT PROGRAM PRODUCT

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

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Applicant(s) wish to disclose the following information.

Technology Center 2100

REFERENCES

The applicant(s) wish to make of record the references cited in the attached European Search Report listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.

☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.

☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

☐ Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.

□ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number <u>15-0030</u>. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND MAIER & NEUSTADT, P.C.

Marvin J. Spivak

Registration No. 24,913

Joseph A. Scafetta, Jr. Registration No. 26, 803

Customer Number

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U.S. PATENT DOCUMENTS							
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
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	AZ				Addit	ional Refe	rences sheet(s) attached
Examiner					Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in							
conformance and not considered. Include copy of this form with next communication to applicant.							